

|   |  |                                     |                                       |                                     |                          |
|---|--|-------------------------------------|---------------------------------------|-------------------------------------|--------------------------|
| <b>PCN Number:</b>                        | 20210614000.1  |                                     | <b>PCN Date:</b>                      | June 14, 2021                       |                          |
| <b>Title:</b>                             | Qualification of new Fab site (FFAB) using qualified Process Technology, Die Revision and additional Assembly site (CDAT) for the THS6212IRHFR/T |                                     |                                       |                                     |                          |
| <b>Customer Contact:</b>                  | <a href="#">PCN Manager</a>  |                                     | <b>Dept:</b>                          | Quality Services                    |                          |
| <b>Proposed 1<sup>st</sup> Ship Date:</b> | Sept 12, 2021  |                                     | <b>Estimated Sample Availability:</b> | Date provided at sample request.    |                          |
| <b>Change Type:</b>                       |  |                                     |                                       |                                     |                          |
| <input checked="" type="checkbox"/>       | Assembly Site  | <input type="checkbox"/>            | Assembly Process                      | <input checked="" type="checkbox"/> | Assembly Materials       |
| <input checked="" type="checkbox"/>       | Design   | <input checked="" type="checkbox"/> | Electrical Specification              | <input type="checkbox"/>            | Mechanical Specification |
| <input type="checkbox"/>                  | Test Site  | <input type="checkbox"/>            | Packing/Shipping/Labeling             | <input type="checkbox"/>            | Test Process             |
| <input type="checkbox"/>                  | Wafer Bump Site  | <input type="checkbox"/>            | Wafer Bump Material                   | <input type="checkbox"/>            | Wafer Bump Process       |
| <input checked="" type="checkbox"/>       | Wafer Fab Site   | <input checked="" type="checkbox"/> | Wafer Fab Materials                   | <input checked="" type="checkbox"/> | Wafer Fab Process        |
|   |  | <input type="checkbox"/>            | Part number change                    |                                     |                          |

### Notification Details

#### Description of Change:

Texas Instruments is pleased to announce the qualification of a new Fab site (FFAB) using qualified Process Technology, Die Revision and additional Assembly site (CDAT) for the THS6212IRHFR/T:

| Current Fab Site |         |                | Additional Fab Site |         |                |
|------------------|---------|----------------|---------------------|---------|----------------|
| Current Fab Site | Process | Wafer Diameter | New Fab Site        | Process | Wafer Diameter |
| D-LIN            | BICOM2X | 150 mm         | FFAB                | BICOMHD | 200 mm         |

Construction difference are noted below:

|                | MLA     | CARZ       | CDAT                    |
|----------------|---------|------------|-------------------------|
| Mount Compound | 4205846 | SID#435143 | <a href="#">4223772</a> |
| Mold Compound  | 4208625 | SID#441086 | <a href="#">4222198</a> |
| MSL            | 3       | 2          | 2                       |

Additionally, as part of the FFAB qualification, there are datasheet modifications necessary. Datasheet changes are as follows:



| Changes from Revision D (November 2019) to Revision E (May 2021)   | Page |
|--|------|
| • Updated the numbering format for tables, figures, and cross-references throughout the document.....                                  | 1    |
| • Changed mid-bias mode value from 17.7 mA to 17.5 mA in <i>Features</i> list .....  | 1    |
| • Changed low-bias mode value from 12.2 mA to 11.9 mA in <i>Features</i> list .....  | 1    |
| • Changed voltage noise value from 2.7 nV/ $\sqrt{\text{Hz}}$ to 2.5 nV/ $\sqrt{\text{Hz}}$ in <i>Features</i> list .....              | 1    |
| • Changed inverting current noise value from 17 pA/ $\sqrt{\text{Hz}}$ to 18 pA/ $\sqrt{\text{Hz}}$ in <i>Features</i> list .....      | 1    |
| • Changed noninverting current noise value from 1.2 pA/ $\sqrt{\text{Hz}}$ to 1.4 pA/ $\sqrt{\text{Hz}}$ in <i>Features</i> list ..... | 1    |
| • Changed HD2 distortion from -100 dBc to -86 dBc in <i>Features</i> list .....  | 1    |
| • Changed HD3 distortion from -89 dBc -101 dBc in <i>Features</i> list .....   | 1    |
| • Changed output current from > 416 mA to > 665 mA in <i>Features</i> list .....   | 1    |
| • Changed output swing from 43.2 Vpp to 49 Vpp in <i>Features</i> list .....   | 1    |
| • Changed bandwidth from 150 MHz to 205 MHz in <i>Features</i> list .....  | 1    |
| • Changed PSRR from 50 dB to > 55 dB in <i>Features</i> list .....   | 1    |
| • Changed thermal protection from 170°C to 175°C in <i>Features</i> list .....   | 1    |
| • Changed differential distortion to HD2 and updated values in <i>Description</i> section.....   | 1    |
| • Changed output swing from 43.2Vpp to 49Vpp in <i>Description</i> section.....  | 1    |
| • Changed power supplies from $\pm 12\text{-V}$ to 28-V in <i>Description</i> section.....   | 1    |
| • Changed current drive from 416-mA to 650-mA in <i>Description</i> section.....   | 1    |
| • Removed YS bond pad package from document.....   | 1    |
| • Changed <i>Typical Line-Driver Circuit Using the THS6212</i> figure.....   | 1    |
| • Removed YS die package and <i>Bond Pad Functions</i> table.....  | 5    |
| • Deleted Output current, IO from <i>Absolute Maximum Ratings</i> .....  | 6    |
| • Added Bias control pin voltage in <i>Absolute Maximum Ratings</i> .....  | 6    |
| • Added Input voltage to all pins except VS+, VS-, and BIAS control in <i>Absolute Maximum Ratings</i> .....                           | 6    |
| • Added Input current limit in <i>Absolute Maximum Ratings</i> .....   | 6    |
| • Changed Maximum junction, TJ from 130 C to 125 C in <i>Absolute Maximum Ratings</i> .....  | 6    |
| • Deleted ESD MM in <i>ESD Ratings</i> .....   | 6    |
| • Changed Operating junction temperature from 130°C to 125°C in <i>Recommended Operating Conditions</i> .....                          | 6    |
| • Added Minimum ambient operating air temperature spec in <i>Recommended Operating Conditions</i> .....                                | 6    |
| • Changed R <sub>ΘJA</sub> from 33.2 °C/W to 42.3 °C/W in <i>Thermal Information</i> .....   | 6    |

|   |    |
|---|----|
| • Changed $R_{\theta JC(Top)}$ from 31.7 °C/W to 32.8 °C/W in <i>Thermal Information</i> .....  | 6  |
| • Changed $R_{\theta JB}$ from 11.3 °C/W to 20.9 °C/W in <i>Thermal Information</i> .....   | 6  |
| • Changed $\psi_{JT}$ from 0.4 °C/W to 3.8 °C/W in <i>Thermal Information</i> .....   | 6  |
| • Changed $\psi_{JB}$ from 11.3 °C/W to 20.9 °C/W in <i>Thermal Information</i> .....   | 6  |
| • Changed $\psi_{JC(bot)}$ from 3.9 °C/W to 9.5 °C/W in <i>Thermal Information</i> .....  | 6  |
| • Added Electrical Characteristics: $V_S = 12V$ table.....  | 7  |
| • Deleted Electrical Characteristics: $V_S = \pm 6 V$ table.....  | 7  |
| • Added Electrical Characteristics: $V_S = 28V$ table .....   | 9  |
| • Deleted Deleted Electrical Characteristics: $V_S = \pm 12 V$ table.....   | 9  |
| • Changed $t_{ON}$ from 1 $\mu$ s to 25ns in <i>Timing Requirements</i> .....   | 10 |
| • Changed $t_{OFF}$ from 1 $\mu$ s to 275ns in <i>Timing Requirements</i> .....   | 10 |
| • Added Typical Characteristics: $V_S = 12 V$ .....   | 11 |
| • Deleted Typical Characteristics: $V_S = \pm 6 V$ (Full Bias).....   | 11 |
| • Deleted Typical Characteristics: $V_S = \pm 6 V$ (Mid Bias).....  | 11 |
| • Deleted Typical Characteristics: $V_S = \pm 6 V$ (Low Bias).....  | 11 |
| • Added Typical Characteristics: $V_S = 28 V$ .....   | 17 |
| • Deleted Typical Characteristics: $V_S = \pm 12 V$ (Full Bias).....  | 17 |
| • Deleted Typical Characteristics: $V_S = \pm 12 V$ (Mid Bias).....   | 17 |
| • Deleted Typical Characteristics: $V_S = \pm 12 V$ (Low Bias).....   | 17 |
| • Changed output swing from 43.2 Vpp to 49 Vpp in <i>Overview</i> section.....  | 20 |
| • Changed current drive from 416 mA to 650 mA in <i>Overview</i> section.....   | 20 |
| • Changed thermal protection junction temperature from 170°C to 175°C in <i>Overview</i> section.....   | 20 |
| • Deleted <i>Output Current and Voltage</i> section.....  | 20 |
| • Added <i>Output Voltage and Current Drive</i> section.....  | 20 |
| • Changed referenced figures for $R_S$ versus capacitive load in <i>Driving Capacitive Loads</i> section.....   | 21 |
| • Changed $\pm 12$ -V supplies to 28-V supply in <i>Distortion Performance</i> section.....   | 22 |
| • Changed $\pm 6$ -V supplies to 12-V supply in <i>Distortion Performance</i> section.....  | 22 |
| • Changed noise evaluation from <a href="#">Section 8.2.2</a> to <a href="#">Figure 8-1</a> in <i>Differential Noise Performance</i> section.....               | 22 |
| • Added $R_S = 50 \Omega$ in <i>Differential Noise Performance</i> section.....   | 22 |
| • Changed 38.9 nV/ $\sqrt{Hz}$ calculation to 53.3 nV/ $\sqrt{Hz}$ in <i>Differential Noise Performance</i> section.....  | 22 |
| • Changed 7 nV/ $\sqrt{Hz}$ calculation to 6.5 nV/ $\sqrt{Hz}$ in <i>Differential Noise Performance</i> section.....  | 22 |
| • Changed output offset calculation to typical rather than worst case in <i>DC Accuracy and Offset Control</i> section.....                                     | 24 |
| • Changed quiescent current value from 23 mA to 19.5 mA in <i>Wideband Current-Feedback Operation</i> section.....  | 25 |
| • Changed swing from 1.9 V from either rail to 49 Vpp in <i>Wideband Current-Feedback Operation</i> section.....  | 25 |
| • Changed current drive from 416 mA to 650 mA in <i>Wideband Current-Feedback Operation</i> section.....  | 25 |
| • Changed $\pm 6 V$ supply to 28 V supply in <i>Wideband Current-Feedback Operation</i> section.....  | 25 |
| • Changed 140 MHz bandwidth to 285 MHz in <i>Wideband Current-Feedback Operation</i> section.....   | 25 |
| • Changed <i>Noninverting Differential I/O Amplifier</i> figure in <i>Wideband Current-Feedback Operation</i> section.....                                      | 25 |
| • Changed <i>Frequency Response and Harmonic Distortion</i> figures in <i>Application Curves</i> section.....   | 26 |
| • Changed <i>Dual-Supply Downstream Driver</i> figure.....  | 27 |
| • Changed supply voltages to $\pm 14 V$ in <i>Line Driver Headroom Requirements</i> section.....  | 28 |
| • Changed quiescent current value from 23 mA to 19.5 mA and $\pm 12 V$ to $\pm 14 V$ in <i>Computing Total Driver Power for Line-Driving Applications</i> ..... | 30 |
| • Changed 23 mA to 19.5 mA, 24 V to 28 V and 1003 mW to 11 mW in <i>Computing Total Driver Power for Line-Driving Applications</i> .....                        | 30 |
| • Changed supply range from " $\pm 5 V$ to $\pm 14 V$ " to " $10 V$ to $28 V$ " in <i>Power Supply Recommendations</i> section..                                | 31 |
| • Changed referenced figures for $R_S$ versus capacitive load in <i>Driving Capacitive Loads</i> section.....   | 32 |
| • Deleted <i>Wafer and Die Information</i> section.....   | 32 |
| • Changed $\pm 12$ -V to 28-V in <i>Layout Guidelines</i> section.....  | 32 |

| Device Family | Change From: | Change To: |
|---------------|--------------|------------|
| THS6212       | SBOS758D     | SBOS758E   |

These changes may be reviewed at the datasheet links provided.

<http://www.ti.com/product/THS6212>

**Reason for Change:**

These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

**Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):**

None.

**Anticipated impact on Material Declaration**

|                          |                                       |                                     |  |
|--------------------------|---------------------------------------|-------------------------------------|--|
| <input type="checkbox"/> | No Impact to the Material Declaration | <input checked="" type="checkbox"/> | Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained at the site link below<br><a href="http://www.ti.com/quality/docs/materialcontentsearch.tsp">http://www.ti.com/quality/docs/materialcontentsearch.tsp</a> |
|--------------------------|---------------------------------------|-------------------------------------|--|

**Changes to product identification resulting from this PCN:**

**Fab Site Information:**

| Chip Site       | Chip Site Origin Code (20L) | Chip Site Country Code (21L) | Chip Site City  |
|-----------------|-----------------------------|------------------------------|-----------------|
| D-LIN           | DLN                         | USA                          | Dallas          |
| <b>FR-BIP-1</b> | <b>TID</b>                  | <b>DEU</b>                   | <b>Freising</b> |

**Die Rev:**

|                |                     |
|----------------|---------------------|
| <b>Current</b> | <b>New</b>          |
| Die Rev [2P]   | <b>Die Rev [2P]</b> |
| <b>A</b>       | <b>A</b>            |

**Assembly Site Information:**

| Assembly Site | Assembly Site Origin (22L) | Assembly Country Code (23L) | Assembly City  |
|---------------|----------------------------|-----------------------------|----------------|
| MLA           | MLA                        | MYS                         | Kuala Lumpur   |
| CARZ          | CSZ                        | CHN                         | Jiangsu        |
| <b>CDAT</b>   | <b>CDA</b>                 | <b>CHN</b>                  | <b>Chengdu</b> |

Sample product shipping label (not actual product label)

**TEXAS INSTRUMENTS**  
 MADE IN: Malaysia  
 2DC: 20:  
 MSL 2 /260C/1 YEAR SEAL DT  
 MSL 1 /235C/UNLIM 03/29/04  
 OPT:  
 ITEM: 39  
**LBL: 5A (L)T0:1750**

(1P) SN74LS07NSR  
 (Q) 2000 (D) 0336  
 (31T) LOT: 3959047MLA  
 (4W) TKY (1T) 7523483S12  
 (P)  
 (2P) REV: (V) 0099317  
 (20L) CSO: SHE (21L) CCO: USA  
 (22L) ASO: MLA (23L) ACO: MYS

**Product Affected:**

THS6212IRHFR

~~THS6212IRHFR~~

THS6212IRHFT



TI Information  
Selective Disclosure

Approve Date 13-May-2021

**Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

| Type  | Test Name / Condition         | Duration                 | Qual Device:<br>THS6212IRHFR | QBS Process<br>Reference:<br>OPA2810IDGK | QBS Package Reference:<br>THS6222IRHFR |
|-------|-------------------------------|--------------------------|------------------------------|--|--|
| HTOL  | Life Test, 78C <sup>A</sup>   | 300 Hours                | -                            | -  | 1/77/0                                 |
| HTOL  | Life Test, 125C               | 1000 Hours               | -                            | 3/231/0                                  | -                                      |
| ELFR  | Early Life Failure Rate, 125C | 48 Hours                 | -                            | 3/3000/0                                 | -                                      |
| ED    | Electrical Characterization   | Per Datasheet Parameters | 1/Pass                       | 3/90/0                                   | 1/Pass                                 |
| HBM   | ESD - HBM                     | 2500 V                   | -                            | 3/9/0                                    | -                                      |
| HBM   | ESD - HBM                     | 3500 V                   | -                            | -  | 1/3/0                                  |
| HBM   | ESD - HBM                     | 4000 V                   | 1/3/0                        | -  | -                                      |
| CDM   | ESD - CDM                     | 1250 V                   | -                            | -  | 1/3/0                                  |
| CDM   | ESD - CDM                     | 1500 V                   | 1/3/0                        | 3/9/0                                    | -                                      |
| LU    | Latch-up                      | Per JESD78               | 1/6/0                        | 3/18/0                                   | 1/6/0                                  |
| HAST  | Biased HAST, 130C/85%RH       | 96 Hours                 | -                            | 3/231/0                                  | 3/231/0                                |
| HTSL  | High Temp Storage Bake 170C   | 420 Hours                | -                            | 3/231/0                                  | 3/231/0                                |
| TC    | Temperature Cycle, -65/150C   | 500 Cycles               | 1/77/0                       | 3/231/0                                  | 3/231/0                                |
| UHAST | Unbiased HAST 130C/85%RH      | 96 Hours                 | 1/77/0                       | 3/231/0                                  | 3/231/0                                |

- QBS: Qual By Similarity
  - Qual Device THS6212IRHFR is qualified at LEVEL2-260C
  - Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
  - The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
  - The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
  - The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
- Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

**Green/Pb-free Status:**

- Qualified Pb-Free (SMT) and Green
- <sup>A</sup> Self heating of die brings Tj up to 150C

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

| Location     | E-Mail   |
|--------------|--|
| USA          | <a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a> |
| Europe       | <a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>     |
| Asia Pacific | <a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>         |
| WW PCN Team  | <a href="mailto:PCN_ww_admin_team@list.ti.com">PCN_ww_admin_team@list.ti.com</a>   |

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